IN THE CLAIMS

Please amend Claims 1, 5, 6, 13, 14, 17 and 18 to read as follows.

1. (Currently Amended) A ferroelectric thin film element comprising a substrate and an epitaxial ferroelectric thin film that has a plurality of crystal faces and that is provided on said substrate: substrate,

wherein said epitaxial ferroelectric thin film satisfies a relation $z/z_0 > 1.003$, wherein a crystal face parallel to a crystal face of a surface of the said substrate, among the crystal faces of said epitaxial ferroelectric thin film, is taken as a Z crystal face, a face spacing of said the Z crystal face is taken as z and a space face spacing of the Z crystal face of a material constituting said epitaxial ferroelectric thin film in a bulk state is taken as z_0 , and

wherein said epitaxial ferroelectric thin film also satisfies a relation $0.997 \le x/x_0 \le 1.003$, wherein one of the crystal faces of said epitaxial ferroelectric thin film perpendicular to the Z crystal face is taken as an X crystal face, a face spacing of the X crystal face is taken as x and a face spacing of the X crystal face of the material constituting said epitaxial ferroelectric thin film in a bulk state is taken as x_0 .

- 2. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a thickness within a range of 2 to 100 nm.
- 3. (Original) A ferroelectric thin film element according to claim 1, further comprising at least a buffer layer between said substrate and said epitaxial ferroelectric thin film.

- 4. (Original) A ferroelectric thin film element according to claim 3, wherein at least one of said substrate and said buffer layer is electroconductive.
- 5. (Currently Amended) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a crystal orientation degree of the Z crystal face of said epitaxial ferroelectric thin film, measured by a $2\theta/\theta$ method with an X-ray incident angle θ to the Z crystal face, is 90 % or higher.
- 6. (Currently Amended) A ferroelectric thin film element according to claim 1, wherein said the Z crystal face has a crystal orientation degree of 99 % or higher.
- 7. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a perovskite structure.
- 8. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film includes a lead (Pb) atom or an oxygen (O) atom as a constituent atom.
- 9. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a tetragonal crystal structure and the Z crystal face is a (001) face.

- 10. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a rhombohedral crystal structure and the Z crystal face is a (111) face.
- 11. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a hexagonal crystal structure and the Z crystal face is a (0001) face.
- 12. (Original) A ferroelectric thin film element according to claim 1, wherein said epitaxial ferroelectric thin film has a rhombic crystal structure and the Z crystal face is a (011) face.
- 13. (Currently Amended) A piezoelectric actuator comprising a substrate and an epitaxial ferroelectric film that has a plurality of crystal faces and that is provided on said substrate: substrate.

wherein said epitaxial ferroelectric film satisfies a relation $z/z_0 > 1.003$, wherein a crystal face parallel to a crystal face of a surface of the said substrate, among the crystal faces of said epitaxial ferroelectric film, is taken as a Z crystal face, a face spacing of said the Z crystal face is taken as z and a space face spacing of the Z crystal face of a material constituting said epitaxial ferroelectric film in a bulk state is taken as z_0 , and

wherein said epitaxial ferroelectric film also satisfies a relation $0.997 \le x/x_0 \le 1.003$, wherein one of the crystal faces of said epitaxial ferroelectric film perpendicular to the Z crystal face is taken as an X crystal face, a face spacing of the X crystal face is taken as x and a face spacing of the X crystal face of the material constituting said epitaxial ferroelectric film in a bulk state is taken as x_0 .

- 14. (Currently Amended) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric thin-film has a thickness within a range of 100 nm to 10 μ m.
- 15. (Original) A piezoelectric actuator according to claim 13, further comprising at least a buffer layer between said substrate and said epitaxial ferroelectric film.
- 16. (Original) A piezoelectric actuator according to claim 15, wherein at least one of said substrate and said buffer layer is electroconductive.
- 17. (Currently Amended) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a crystal orientation degree of the Z crystal face of said epitaxial ferroelectric film, measured by a 2 θ/θ method with an X-ray incident angle θ to the Z crystal face, is 90 % or higher.
- 18. (Currently Amended) A piezoelectric actuator according to claim 13, wherein said the Z crystal face has a crystal orientation degree of 99 % or higher.

- 19. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a perovskite structure.
- 20. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film includes a lead (Pb) atom or an oxygen (O) atom as a constituent atom.
- 21. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a tetragonal crystal structure and the Z crystal face is a (001) face.
- 22. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a rhombohedral crystal structure and the Z crystal face is a (111) face.
- 23. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a hexagonal crystal structure and the Z crystal face is a (0001) face.
- 24. (Original) A piezoelectric actuator according to claim 13, wherein said epitaxial ferroelectric film has a rhombic crystal structure and the Z crystal face is a (011) face.

25. (Original) A liquid discharge head for discharging a liquid utilizing a piezoelectric actuator according to claim 13.